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Substitute for form 1449A/PTO				<i>Complete if Known</i>	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	Based on 10/214,691
				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
Sheet	1	of	12	Attorney Docket Number	0756-7218

U.S. PATENT DOCUMENTS					
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code <sup>2</sup> (if known)		
PY		5,686,328		Zhang et al.	11/11/97
		5,763,899		Yamazaki et al.	06/09/98
		5,782,665		Weisfield et al.	07/21/98
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
		Japan J. Appl. Phys. 8 (1969) 1056, "Effect of Deposited Metals on the Crystallization Temperature of Amorphous Germanium Film," OKI et al.	
		Technology Information Association, "Thermo-Auto-Chrome Full Color Recording Technology," May 31, 1995	

Examiner Signature	<i>[Signature]</i>	Date Considered	08/23/05
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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PB		5,811,327		Funai et al.	09/22/98
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		Office <sup>3</sup>	Number <sup>4</sup> (if known)			Kind Code <sup>2</sup> (if known)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		JP	07-335900	Teramoto Satoshi	12/22/95		Abst.
		JP	64-081324		03/27/89		Abst.
OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS							
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✓		IBM Technical Disclosure Bulletin, Vol. 11, No.7, A.R. Baker, Jr.					

Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	<i>8/23/03</i>
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Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	<i>8/23/08</i>
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Examiner Signature	<i>fetsum abraham</i>	Date Considered	<i>8/23/03</i>
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Sheet

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Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	<i>2/8/05</i>
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	Based on 10/214,691
				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
Sheet	8	of	12	Attorney Docket Number	0756-7218

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
FB		Thompson et al., "Silicide Formation in Pd-a-Si:H Schottky Barriers," August 1981, pp. 274-276, Appl. Phys. Lett., Vol. 39, No. 3	
		Nemanich et al., "Initial Phase Formation at the Interface of Ni, Pd, or Pt and Si," 1984, pp. unknown, Mat. Res. Soc. Symp. Proc., Vol. 25	
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		Hayzelden et al., "Silicide Formation and Silicide Mediated Crystallization of Nickel-Implanted Amorphous Silicon Thin Films," May 15, 1993, pp. 8279-8289, J. Appl. Phys. 73(12)	

Examiner Signature	<i>John Kehan</i>	Date Considered	2/8/03
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				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
Sheet	9	of	12	Attorney Docket Number	0756-7218

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY
		Number	Kind Code <sup>2</sup> (if known)		
(P)		5,705,829		Miyanaga et al.	01/06/98
		5,712,191		Nakajima et al.	01/27/98
		5,756,364		Tanaka et al.	05/26/98
		5,619,044		Makita et al.	04/08/97
		5,530,266		Yonehara et al.	06/25/96
		5,550,070		Funai et al.	08/27/96
		5,693,959		Inoue et al.	12/02/97

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		Kuznetsov et al., "Silicide Precipitate Formation and Solid Phase Re-Growth of Ni-Implanted Amorphous Silicon," April 5-8, 1993, pp. 191-194, Inst. Phys. Conf. Ser. No. 134.4: Proceedings of Royal Microscopical Society Conf.	
		Liu et al., "Polycrystalline Silicon Thin Film Transistors on Corning 7059 Glass Substrates Using Short Time, Low-Temperature Processing," May 17, 1993, pp. 2554-2556, Appl. Phys. Lett 62(20)	
		Liu et al., "Selective Area Crystallization of Amorphous Silicon Films by Low-Temperature Rapid Thermal Annealing," August 14, 1989, pp. 660-662, Appl. Phys. Lett 55(7)	
		Spaepen et al., Metal-Enhanced Growth of Silicon, 1992, pp. 483-499, Crucial Issues in Semiconductor Materials & Processing Technologies	

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		5,403,772		Zhang et al.	04/04/95
		5,426,064		Zhang et al.	06/20/95
		5,481,121		Zhang et al.	01/02/96
		5,488,000		Zhang et al.	01/30/96
		5,492,843		Adachi et al.	02/20/96
		5,501,989		Takayama et al.	03/26/96
		5,508,533		Takemura	04/16/96
		5,529,937		Zhang et al.	06/25/96
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		5,543,352		Ohtani et al.	08/06/96
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		5,605,846		Ohtani et al.	02/25/97
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		5,663,077		Adachi et al.	09/02/97
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		5,696,386		Yamazaki	12/09/97
		5,696,388		Funada et al.	12/09/97
		5,700,333		Yamazaki et al.	12/23/97

Examiner Signature	<i>Fetsum Abraham</i>	Date Considered	8/30/01
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Sheet	11	of	12	Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
				Attorney Docket Number	0756-7218

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		Number	Kind Code <sup>2</sup> (if known)		
		5,932,893		Miyanaga et al.	08/03/99
		4,759,610		Yanagisawa	07/26/88
		5,535,471		Guldi	07/16/96
		5,661,056		Takeuchi	08/26/97
		4,140,548		Zimmer	02/20/79
		5,210,050		Yamazaki et al.	05/11/93
		5,298,075		Lagendijk et al.	03/29/94
		5,306,651		Masumo et al.	04/26/94
		5,313,076		Yamazaki et al.	05/17/94
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R		Wolf, <i>Silicon Processing for the VLSI Era</i> , Volume 2, Chapter 4, page 274 (1990).	

Examiner Signature Fetsum Abraham Date Considered 8/30/05

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				Filing Date	August 9, 2002
				First Named Inventor	Shunpei YAMAZAKI, et al.
				Group Art Unit	2826
				Examiner Name	Fetsum Abraham
Sheet	12	of	12	Attorney Docket Number	0756-7218

## **U.S. PATENT DOCUMENTS**

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		Office <sup>3</sup>	Number <sup>4</sup>				
		JP	06-314785		11/08/94		Ab
		JP	06-314787		11/08/94		Ab

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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>		Application Number	10/712,062
		Filing Date	November 14, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Group Art Unit	2826
		Examiner Name	F. Abraham
Sheet	1	2	Attorney Docket Number
		0756-7218	

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		Number	Kind Code <sup>2</sup> (if known)			
FB		6,162,704		Yamazaki et al.	12/19/2000	
		6,294,441		Yamazaki	09/25/2001	
		6,461,943		Yamazaki et al.	10/08/2002	
		6,620,711		Yamazaki	09/16/2003	
		6,194,254		Takemura	02/27/2001	

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FB		JP	07-066425			03/10/1995		Abst. & U.S. Equiv.
		JP	08-045839			02/16/1996		Abst. & U.S. Equiv.
		JP	08-045840			02/16/1996		Abst. & U.S. Equiv.
		JP	08-097169			04/12/1996		Abst. & U.S. Equiv.
		KR	96-005879			02/23/1996		U.S. Equiv.
		JP	07-045519			02/14/1995		Abst. & U.S. Equiv.
		JP	07-231100			08/29/1995		Abst. & U.S. Equiv.
		JP	07-094757			04/07/1995		Abst. & U.S. Equiv.
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		Filing Date	November 14, 2003
		First Named Inventor	Shunpei YAMAZAKI et al.
		Group Art Unit	2826
		Examiner Name	F. Abraham
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PAPERS RECEIVED NOV 15 2004		Attorney Docket Number	
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AB		2002/0025659		Yamazaki et al.	02/28/2002	
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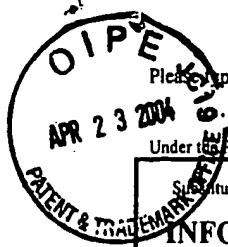
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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(use as many sheets as necessary)</i>				Application Number	10/712,062
				Filing Date	November 14, 2003
				First Named Inventor	Shunpei YAMAZAKI et al.
				Group Art Unit	2826
				Examiner Name	F. Abraham
Sheet	1	of	1	Attorney Docket Number	0756-7218

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Examiner Signature	<u>Tetsuya Shabu</u>	Date Considered	8/23/05
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